Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/533,266	FREEMAN, MATTH	HEW
Examiner	Art Unit	
Pin Shan	1657	

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
WE	ST	4/27/2007	BS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
updated search	4/27/2007	BS
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